# PH5525L

# N-channel TrenchMOS logic level FET Rev. 02 — 5 December 2006

**Product data sheet** 

## **Product profile**

#### 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology.

#### 1.2 Features

- Logic level threshold
- Optimized for use in DC-to-DC converters
- 100 % R<sub>G</sub> tested

- Lead-free package
- Very low switching and conduction losses

#### 1.3 Applications

- DC-to-DC converters
- Voltage regulators

- Switched-mode power supplies
- PC Motherboards

#### 1.4 Quick reference data

- $V_{DS} \le 25 \text{ V}$
- $\blacksquare$  R<sub>DSon</sub>  $\leq 5.5$  m $\Omega$

- $I_D \le 81.7 \text{ A}$
- $Q_{GD} = 3.3 \text{ nC (typ)}$

# **Pinning information**

**Pinning** Table 1.

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Pin	Description	Simplified outline	Symbol	
1, 2, 3	source (S)		_	
4	gate (G)	mb	Ď	
mb	mounting base; connected to drain (D)	1 2 3 4	mbb076 S	
		SOT669 (LFPAK)		



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# 3. Ordering information

#### Table 2. Ordering information

Type number	Package		
	Name	Description	Version
PH5525L	LFPAK	plastic single-ended surface-mounted package; 4 leads	SOT669

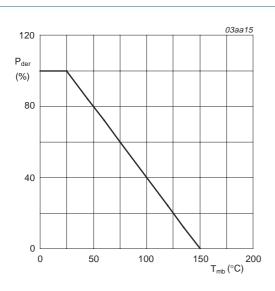
# 4. Limiting values

#### Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

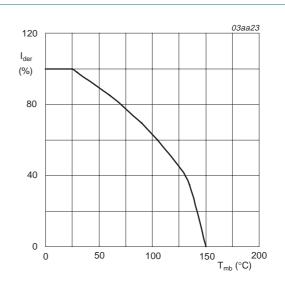
Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 150 °C	-	25	V
$V_{DGR}$	drain-gate voltage (DC)	$25  ^{\circ}\text{C} \le \text{T}_{j} \le 150  ^{\circ}\text{C};  \text{R}_{\text{GS}} = 20  \text{k}\Omega$	-	25	V
$V_{GS}$	gate-source voltage		-	±20	V
$I_D$	drain current	$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see <u>Figure 2</u> and <u>3</u>	-	81.7	Α
		$T_{mb}$ = 100 °C; $V_{GS}$ = 10 V; see <u>Figure 2</u>	-	51.7	Α
$I_{DM}$	peak drain current	$T_{mb}$ = 25 °C; pulsed; $t_p \le 10 \mu s$ ; see Figure 3	-	300	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>	-	62.5	W
T <sub>stg</sub>	storage temperature		-55	+150	°C
Tj	junction temperature		-55	+150	°C
Source-c	Irain diode				
Is	source current	T <sub>mb</sub> = 25 °C	-	52	Α
I <sub>SM</sub>	peak source current	$T_{mb}$ = 25 °C; pulsed; $t_p \le 10 \mu s$	-	208	Α
Avalanch	ne ruggedness				
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	unclamped inductive load; $I_D$ = 45 A; $t_p$ = 0.1 ms; $V_{DS} \le 25$ V; $R_{GS}$ = 50 $\Omega;$ $V_{GS}$ = 10 V; starting at $T_j$ = 25 $^{\circ}C$	-	100	mJ

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$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \%$$

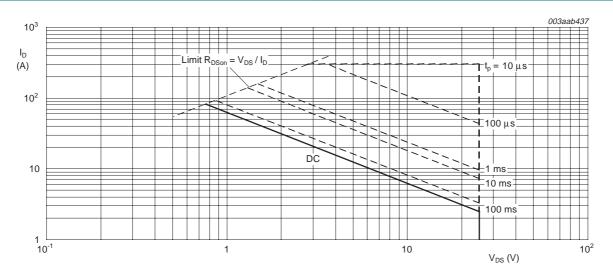
Fig 1. Normalized total power dissipation as a function of mounting base temperature



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100 \%$$

Fig 2. Normalized continuous drain current as a function of mounting base temperature

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 $T_{mb}$  = 25 °C;  $I_{DM}$  is single pulse

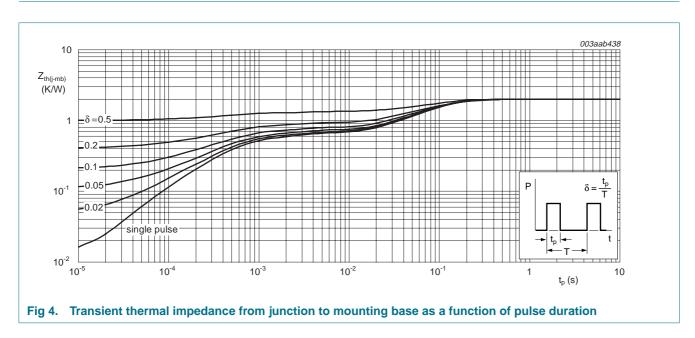
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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## 5. Thermal characteristics

#### Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W



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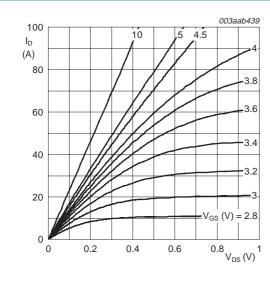
# 6. Characteristics

Table 5. Characteristics

 $T_j = 25 \,^{\circ}C$  unless otherwise specified.

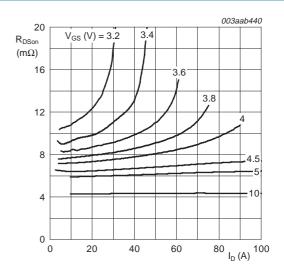
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
V <sub>(BR)DSS</sub>	drain-source breakdown	$I_D = 250 \mu\text{A};  V_{GS} = 0  \text{V}$				
voltage	voltage	T <sub>j</sub> = 25 °C	25	-	-	V
	T <sub>j</sub> = −55 °C	22.5	-	-	V	
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; see <u>Figure 9</u> and <u>10</u>				
		T <sub>j</sub> = 25 °C	1.3	1.7	2.15	V
		T <sub>j</sub> = 150 °C	8.0	-	-	V
		T <sub>j</sub> = −55 °C	-	-	2.6	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}$				
		T <sub>j</sub> = 25 °C	-	-	1	μΑ
		T <sub>j</sub> = 150 °C	-	-	100	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = \pm 16 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	100	nΑ
$R_G$	gate resistance	f = 1 MHz	-	1.8	-	Ω
R <sub>DSon</sub>	drain-source on-state	$V_{GS} = 10 \text{ V}$ ; $I_D = 25 \text{ A}$ ; see Figure 6 and 8	22.5  1.3 0.8			
	T <sub>j</sub> = 150	T <sub>j</sub> = 25 °C	-	4	5.5	$m\Omega$
		T <sub>j</sub> = 150 °C	-	6.8	9.35	$m\Omega$
		$V_{GS} = 4.5 \text{ V}$ ; $I_D = 25 \text{ A}$ ; see Figure 6 and 8	-	5.9	8.2	$m\Omega$
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; $V_{GS} = 4.5 \text{ V}$ ;	-	16.6	-	nC
$Q_{GS}$	gate-source charge	see <u>Figure 11</u> and <u>12</u>	-	8	-	nC
Q <sub>GS1</sub>	pre-V <sub>GS(th)</sub> gate-source charge		-	3.4	-	nC
Q <sub>GS2</sub>	post-V <sub>GS(th)</sub> gate-source charge		-	4.6	-	nC
$Q_{GD}$	gate-drain charge		-	3.3	-	nC
$V_{GS(pl)}$	gate-source plateau voltage		-	3.1	-	V
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 12 \text{ V}; f = 1 \text{ MHz};$	-	2150	-	pF
C <sub>oss</sub>	output capacitance	see <u>Figure 14</u>	-	500	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	225	-	pF
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 0 \text{ V}; f = 1 \text{ MHz}$	-	2460	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 12 V; $R_L$ = 0.5 $\Omega$ ; $V_{GS}$ = 4.5 V;	-	25	-	ns
t <sub>r</sub>	rise time	$R_G = 5.6 \Omega$		55	-	ns
t <sub>d(off)</sub>	turn-off delay time			28	-	ns
t <sub>f</sub>	fall time		-	17	-	ns
Source-d	drain diode					
$V_{SD}$	source-drain voltage	I <sub>S</sub> = 25 A; V <sub>GS</sub> = 0 V; see <u>Figure 13</u>	-	0.83	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V}$	-	33.2	-	ns
Q <sub>r</sub>	recovered charge		-	10.8	-	nC

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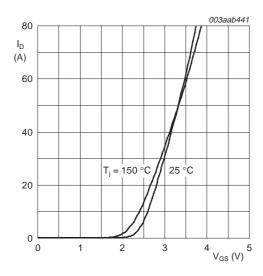
T<sub>j</sub> = 25 °C

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



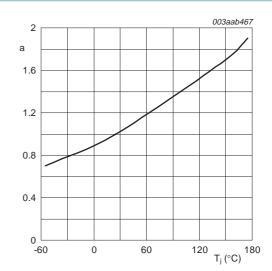
T<sub>j</sub> = 25 °C

Fig 6. Drain-source on-state resistance as a function of drain current; typical values



 $T_i = 25$  °C and 150 °C;  $V_{DS} > I_D \times R_{DSon}$ 

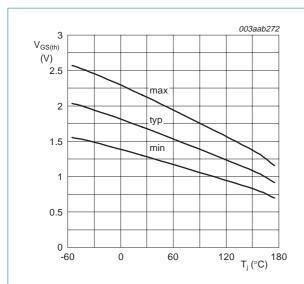
Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values



$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

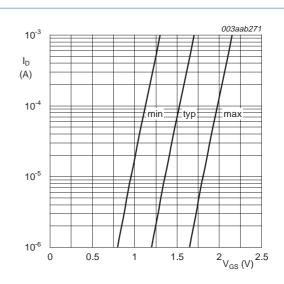
Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature

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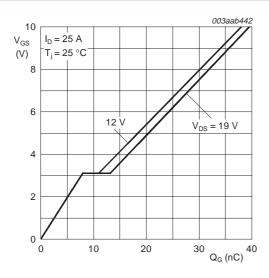
 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$ 

Fig 9. Gate-source threshold voltage as a function of junction temperature



 $T_j$  = 25 °C;  $V_{DS}$  = 5 V

Fig 10. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 25 \text{ A}$ ;  $V_{DS} = 12 \text{ V}$  and 19 V

Fig 11. Gate-source voltage as a function of gate charge; typical values

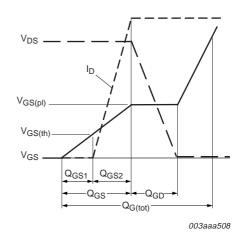
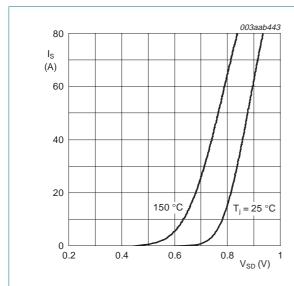


Fig 12. Gate charge waveform definitions

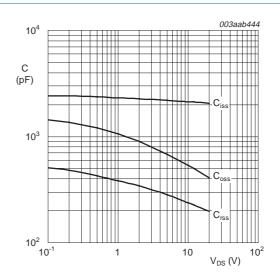
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 $T_j$  = 25 °C and 150 °C;  $V_{GS}$  = 0 V

Fig 13. Source current as a function of source-drain voltage; typical values



 $V_{GS} = 0 V$ ; f = 1 MHz

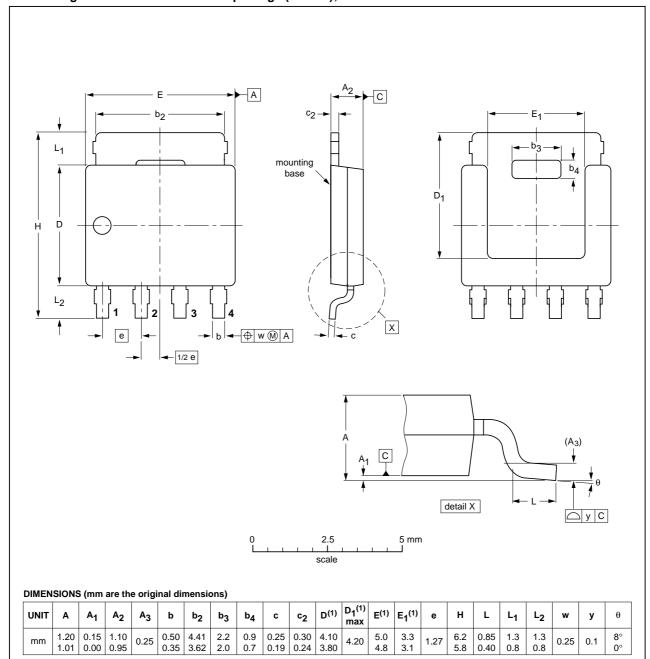
Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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# 7. Package outline

#### Plastic single-ended surface-mounted package (LFPAK); 4 leads

**SOT669** 



#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	ENCES		EUROPEAN PROJECTION	ISSUE DATE
VERSION	IEC	JEDEC	JEITA			ISSUE DATE
SOT669		MO-235				<del>04-10-13</del> 06-03-16

Fig 15. Package outline SOT669 (LFPAK)

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# 8. Revision history

#### Table 6. Revision history

Document ID Release date		Data sheet status	Change notice	Supersedes
PH5525L_2	20061205	Product data sheet	-	PH5525L_1
Modifications:	<ul> <li>Section 1.2: upd</li> </ul>	ated the list		
PH5525L_1	20061010	Product data sheet	-	-

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#### 9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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